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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Masayuki OIKAWA, et al.

GROUP: 2872

SERIAL NO: 10/574,286

FILED: March 31, 2006

EXAMINER:

FOR: INSPECTION METHOD AND INSPECTION ASSISTING DEVICE FOR
QUARTZ PRODUCT OF SEMICONDUCTOR PROCESSING APPARATUS

SUBMISSION OF SUPPLEMENTAL APPLICATION DATA SHEET

Office of Initial Patent Examination
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Applicant(s) submit herewith a Supplemental Application Data Sheet for the above-identified application for the purpose of removing the Assignment Data.

Respectfully Submitted,

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